Search Notes

Application/Control No.	Applicant(s)/Patent under Reexamination
10/644,804	CHEN, CHIH-JU
Examiner	Art Unit
Gopal C. Ray	2111

SEARCHED				
Class	Subclass	Date	Examiner	
710	300- 303,62,74, 313,316	1/20/2006	GCR	
711	100,103	1/20/2006	GCR	
361	684,686	1/20/2006	GCR	
361	737	1/20/2006	GCR	
439	59,79,945	1/20/2006	GCR	
439	638,639	1/20/2006	GCR	
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INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner	
	-			
PGPUB text interferen		1/20/2006	GCR	

SEARCH NOTES (INCLUDING SEARCH STRATEGY)				
	DATE	EXMR		
WEST: USPT, US OCR, EPO ABS, JPO ABS, DWPI, IBM TDB (see search history printouts)	1/20/2006	GCR		
EAST: USPT (see search history printouts)	1/20/2006	GCR		
NPL: IEEE Xplore (see search history printouts)	1/20/2006	GCR		
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